

IGBT

TRENCHSTOP™ IGBT3 Chip SIGC84T120R3E

Data Sheet

Industrial Power Control



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TRENCHSTOP[™] IGBT3 Chip

Features:

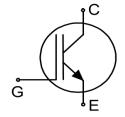
- 1200V trench & field stop technology
- Low turn-off losses
- Short tail current
- Positive temperature coefficient
- Easy paralleling

Recommended for:

Power modules

Applications:

• Drives



Chip Type	V _{CE}	/ Cn ¹	Die Size	Package
SIGC84T120R3E	1200V	75A	9.13mm x 9.15mm	Sawn on foil

Mechanical Parameters

Die size		9.13 x 9.15		
Emitter pad size		See chip drawing	mm²	
Gate pad size		1.319 x 0.820	mm	
Area total		83.54	l	
Thickness		140	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	306		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500μm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
Storago onvironment	for original and sealed MBB bags			
Storage environment	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or humidity <25%RH, temperature 17°C – 25°C, <6		

¹ Nominal collector current at T_C =100°C for chip packaged in power modules, see application example cited on page 5.



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-emitter voltage, T_{vj} =25°C	V _{CE}	1200	V	
DC collector current, limited by $T_{\rm vjmax}^{\ \ 2}$	I _C	-	Α	
Pulsed collector current, t_p limited by $T_{vj \max}^3$	I _{C,puls}	225	Α	
Gate-emitter voltage	V_{GE}	±20	V	
Junction temperature range	$T_{\rm vj}$	-55 +175	°C	
Operating junction temperature	$T_{\rm vj}$	-55 + 150	°C	
Short circuit data $^{3/4}$ V_{GE} =15V, V_{CC} =900V, T_{vj} =125°C	t _{sc}	10	μs	
Reverse bias safe operating area ³ (RBSOA)	<i>I</i> _{C,max} =150A, <i>V</i> _{CE,max} =1200V, <i>T</i> _{vj} ≤125°C			

Static Characteristics (tested on wafer), T_{vj} =25°C

Parameter	Symbol	Conditions	Value			Unit
rai ailletei		Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	V_{GE} =0V, I_{C} =3mA	1200	ı	-	
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =75A	1.4	1.7	2.1	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =3mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	$V_{\text{CE}} = 1200 \text{V}, \ V_{\text{GE}} = 0 \text{V}$	1	1	10.1	μA
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$	-	-	600	nA
Integrated gate resistor	r _G			10		Ω

Electrical Characteristics ³

Parameter	Symbol	Conditions	Value			l lmi4
rarameter			min.	typ.	max.	Unit
Collector-emitter saturation voltage	V _{CEsat}	V_{GE} =15V, I_{C} =75A, T_{vj} =125°C	-	2.0	-	V
Input capacitance	C _{ies}	V _{CE} =25V,	-	5345	-	"F
Reverse transfer capacitance	C _{res}	V_{GE} =0V, f =1MHz T_{Vj} =25°C	-	242	-	pF

² Depending on thermal properties of assembly.

³ Not subject to production test - verified by design/characterization.

⁴ Allowed number of short circuits: <1000; time between short circuits: >1s.



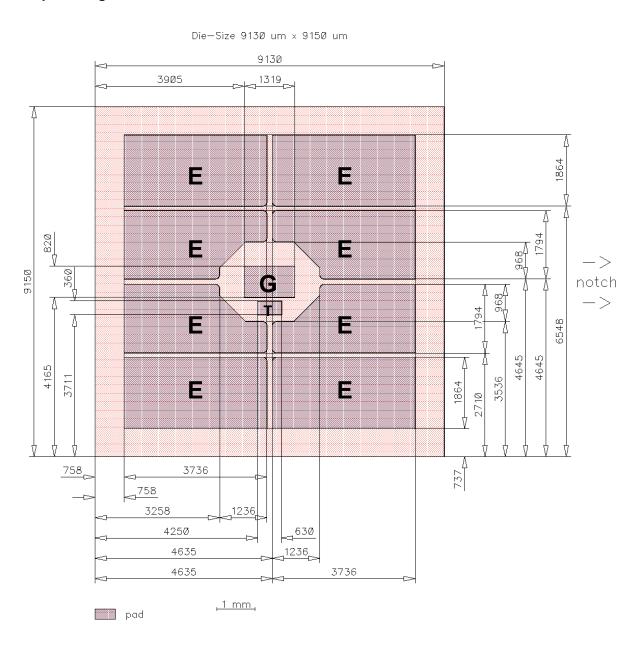
Further Electrical Characteristics

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	FP75R12KE3	Rev. 3.1
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Chip Drawing



E = Emitter

G = Gate

T = Test pad do not contact



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Revision	Subjects (major changes since last revision)	Date
2.2	Change wafer size to 200mm	30.04.2010
2.3	Additional basic types L7677M, L7677T, L7677E; new gate pad design	02.07.2014
2.4	Minor changes, chip drawing	06.02.2015
2.5	Update disclaimer	19.08.2015

Relevant Application Notes



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